Application No. 10/815,567 Attorney Docket No. MP1534 FHFGD Ref. No.: 10368.0003-00000

## **AMENDMENTS TO THE CLAIMS:**

This listing of claims will replace all prior versions and listings of claims in the application:

- (Previously Presented) A method comprising:
  - monitoring one or more sensor outputs measuring a power consumption property of a chip; and
  - recording a time that at least one of the sensor outputs indicates an existence of the power consumption property at a predetermined value.
- (Original) The method of claim 1, wherein the power consumption property of the chip comprises temperature, and the temperature comprises a temperature range including one or more temperatures.
- 3. (Original) The method of claim 2, wherein each sensor output corresponds to a temperature range, and indicates the existence of the one or more temperatures measured at the corresponding sensor output.
- 4. (Original) The method of claim 1, wherein the power consumption property of the chip comprises voltage drop, and the voltage drop range includes one or more voltage drops.
- 5. (Original) The method of claim 4, wherein each sensor output corresponds to a voltage drop range, and each sensor output indicates the existence of a voltage drop measured at the corresponding output.

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6. (Previously Presented) A method for analyzing operation of a chip executing an application, comprising:

monitoring one or more parts of the application by a sensor attached to the chip;

obtaining event data from the sensor, the event data including times that one or more sensor outputs indicates an existence of a power consumption property of the chip at a predetermined value; and

for at least one of the parts of the application, correlating the event data with the parts of the application.

- 7. (Original) The method of claim 6, wherein the power consumption property comprises temperature.
- 8. (Original) The method of claim 6, wherein the power consumption property comprises voltage drop.
- 9. (Previously Presented) An apparatus for analyzing operation of a chip executing an application, comprising:

circuitry capable of:

monitoring one or more parts of the application by a sensor attached to the chip;

obtaining event data from the sensor, the event data including
times that one or more sensor outputs indicates an existence
of a power consumption property of the chip at a
predetermined value; and

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for at least one of the parts of the application, correlating the event data with the parts of the application.

- 10. (Original) The apparatus of claim 9, wherein the power consumption property of the chip comprises temperature, and the temperature comprises a temperature range including one or more temperatures.
- 11. (Original) The apparatus of claim 10, wherein each sensor output corresponds to a temperature range, and indicates the existence of the one or more temperatures measured at the corresponding sensor output.
- 12. (Original) The apparatus of claim 9, wherein the power consumption property of the chip comprises voltage drop, and the voltage drop comprises a voltage drop range including one or more voltage drops.
- 13. (Original) The apparatus of claim 12, wherein each sensor output corresponds to a voltage drop range, and each sensor output indicates the existence of a voltage drop measured at the corresponding output.
- 14. (Previously Presented) A system for analyzing operation of a chip executing an application, comprising:

circuitry on a first node, the circuitry connected to the chip and capable of:

monitoring one or more parts of the application by a sensor attached to the chip;

obtaining event data from the sensor, the event data including times that each of one or more sensor outputs indicates an

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existence of a power consumption property of the chip at a predetermined value; and

for at least one of the parts of the application, correlating the event data with the parts of the application; and

a performance analyzer on a second node, the performance analyzer communicatively coupled to the circuitry on the first node to use the correlated information.

- 15. (Previously Presented) The system of claim 14, wherein the power consumption property of the chip comprises temperature, and the temperature comprises a temperature range including one or more temperatures.
- 16. (Original) The system of claim 15, wherein each sensor output corresponds to a temperature range, and indicates the existence of the one or more temperatures measured at the corresponding sensor output.
- 17. (Original) The system of claim 14, wherein the power consumption property of the chip comprises voltage drop, and wherein the voltage drop range includes one or more voltage drops.
- 18. (Original) The system of claim 17, wherein each sensor output corresponds to a voltage drop range, and each sensor output indicates the existence of a voltage drop measured at the corresponding output.
- 19. (Previously Presented) An article comprising a machine-readable medium having machine-accessible instructions, the instructions when executed by a machine, result in the following:

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monitoring one or more parts of the instructions by a sensor attached to the machine;

obtaining event data from the sensor, the event data including times that each of one or more sensor outputs indicates an existence of a power consumption property of a chip at a predetermined value; and

for at least one of the parts of the instructions, correlating the event data with the parts of the instructions.

- 20. (Original) The article of claim 19, wherein the power consumption property of the chip comprises a temperature range, and wherein the temperature range includes one or more temperatures.
- 21. (Original) The article of claim 20, wherein each sensor output corresponds to a temperature range, and indicates the existence of the one or more temperatures measured at the corresponding sensor output.
- 22. (Original) The article of claim 19, wherein the power consumption property of the chip comprises voltage drop range, and wherein the voltage drop range includes one or more voltage drops.
- 23. (Original) The article of claim 22, wherein each sensor output corresponds to a voltage drop range, and each sensor output indicates the existence of a voltage drop measured at the corresponding output.